

Search Notes

Application/Control No.

10/719,276

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under
Reexamination

LAM ET AL.

Art Unit

1745

SEARCHED

Class	Subclass	Date	Examiner
429	12	11/21/2006	DWY
429	34	11/21/2006	DWY
429	46	11/21/2006	DWY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	11/21/2006	DWY